

INFORMATION DISCLOSURE STATEMENT TRANSMITTAL

To Commissioner For Patents

Enclosed herewith is a Form PTO-1449, any required copies of documents listed thereon, and any concise explanation of their relevance is indicated below per 37 CFR 1.97.

Application Number	10/537028 10/537028
Filing Date	
First Named Inventor	PINEDA DE GYVEZ, Jose
Group Art Unit	2816
Examiner Name	Dinh Le
Atty. Docket Number	NL02 1186 US

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Document Number No.-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns Lines, Where Relevant Passages or Relevant Figures Appear
<i>DL</i>	1	US- 6,040,728	3/21/2000		
		US-			
		US-			
		US-			
		US-			

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Document Number (ctry ² -no.-kind ² , if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of cited document	Pages, Columns Lines, Where Relevant Passages or Relevant Figures Appear	T ⁴

NON-PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	Include name of the author (in capital letters), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ⁴
<i>DL</i>	2	LIU T ET AL: "A negative feedback based substrate coupling noise reduction method", ASIC/SOC Conference, 1999. PROCEEDINGS. TWELFTH ANNUAL IEEE INTERNATIONAL, WASHINGTON, DC, USA 15-18 SEPT. 1999, PISCATAWAY, NJ, USA, IEEE, US, 9/15/1999, pages 49-53	
<i>DL</i>	3	CHAN H.H.Y ET AL: "Substrate coupled noise reduction and active noise suppression circuits for mixed-signal system-on-a-chip designs" PROCEEDINGS OF THE 44 TH . IEEE 2001 MIDWEST SYMPOSIUM ON CIRCUITS AND SYSTEMS. MWSCAS 2001. DAYTON, OH, AUG. 14-17, 2001, MIDWEST SYMPOSIUM ON CIRCUITS AND SYSTEMS, NEW YORK, NY: IEEE, US, vol. 1 of 2, 8/14/2001, pages 154-157	

Examiner Signature	<i>Thanh Le</i>	Date Considered	7/17/06
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* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 18 if possible. ⁶ Applicant to place a check mark here if English language Translation is attached.

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